Planar In-Situ Root Analyzer

Features

1. Non-destructive in-situ planar measurement

2. Capable of acquiring high-resolution color images

3. Capable of capturing images at different root depths to synthesize comprehensive root profile diagrams

4. Capable of fixed-point, continuous observation of root system dynamics throughout the entire growing season

Technical parameters:

Host Resolution	4800*9600 dpi
Image Acquisition Speed	12S
Sensor	CIS
Light Source	LED
Single Scan Width	216mm
Single Scan Depth	297mm
Color Depth	48
Scan Window	Double-sided 1000*267*50 mm